

Notice of References Cited

Application/Control No.

10/653,990

Applicant(s)/Patent Under
Reexamination
SHEU ET AL.

Examiner

Jimmy Lin

Art Unit

1792

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	U	English abstract of WO 02/41348
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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